Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/827,215	CHEN ET AL.	
Examiner	Art Unit	
Greg Bengzon	2144	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
((presence location awareness) near9 (information data filter restrict\$5 context))	12/17	SB	
((gateway base (access adj point) ap bsc msc scp) same ((presence location awareness) adj information)			
((distribut\$3 local) same ((presence location awareness) adj information)			
Double Patent Search			
Inventor / Assignee Search			
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